

# MSKSEMI 美森科

SEMICONDUCTOR



ESD



TVS



TSS



MOV



GDT



PLED

## T2N7002AK-MS

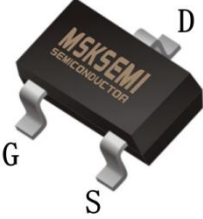
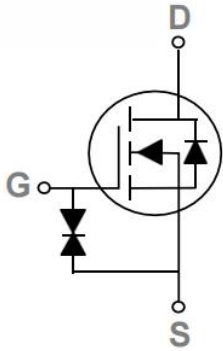

Product specification

## Features

- 60V,0.3A,  $R_{DS(ON)} = 2.2\Omega @ V_{GS}=10V$
- Improved dv/dt capability
- Fast switching
- Green Device Available
- G-S ESD Protection Diode Embedded
- ESD protected up to 2KV

BVDSS	RDSON	ID
60V	2.2Ω	0.3A

## Reference News

PACKAGE OUTLINE	Pin Configuration	Marking
 <p>SOT-23</p>		

## Absolute Maximum Ratings (TA=25°C unless otherwise noted)

Symbol	Parameter	Rating	Units
$V_{DS}$	Drain- Source Voltage	60	V
$V_{GS}$	Gate- Source Voltage	±20	V
$I_D$	Drain Current – Continuous ( $T_C=25^\circ C$ )	0.3	A
	Drain Current – Continuous ( $T_C=100^\circ C$ )	0.1	A
$I_{DM}$	Drain Current – Pulsed <sup>1</sup>	0.8	A
$P_D$	Power Dissipation ( $T_C=25^\circ C$ )	0.35	W
	Power Dissipation – Derate above 25 °c	0.003	W/°C
$T_{STG}$	Storage Temperature Range	-50 to 150	°c
$T_J$	Operating Junction Temperature Range	-50 to 150	°c

## Thermal Characteristics

Symbol	Parameter	Typ.	Max.	Unit
R <sub>θJA</sub>	Thermal Resistance Junction to ambient	---	357	°C/W

## Electrical Characteristics(T<sub>J</sub>=25 °C , unless otherwise noted)

### Off Characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BV <sub>DSS</sub>	Drain- Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =250uA	60	---	---	V
I <sub>DSS</sub>	Drain- Source Leakage Current	V <sub>DS</sub> =60V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C	---	---	1	μA
		V <sub>DS</sub> =48V , V <sub>GS</sub> =0V , T <sub>J</sub> =125°C	---	---	10	μA
I <sub>GSS</sub>	Gate- Source Leakage Current	V <sub>GS</sub> ±20V , V <sub>DS</sub> =0V	---	---	±10	μA

### On Characteristics

R <sub>DS(ON)</sub>	Static Drain- Source On- Resistance	V <sub>GS</sub> =10V , I <sub>D</sub> =0.3A	---	2.2	2.8	Ω
		V <sub>GS</sub> =4.5V , I <sub>D</sub> =0.2A	---	2.4	3.0	Ω
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =250uA	1	1.6	2.5	V
g <sub>fs</sub>	Forward Transconductance	V <sub>DS</sub> =10V , I <sub>D</sub> =0.3A	---	0.5	---	S

### Dynamic and switching Characteristics

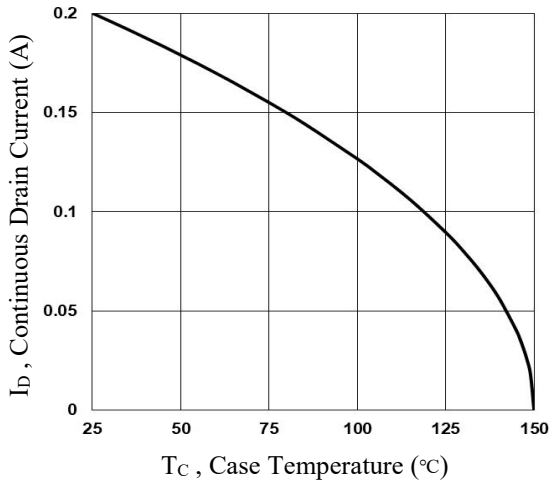
Q <sub>g</sub>	Total Gate Charge <sup>2 , 3</sup>	V <sub>DS</sub> =30V , V <sub>GS</sub> =10V , I <sub>D</sub> =1A	---	3.7	5.6	nC
Q <sub>gs</sub>	Gate-Source Charge <sup>2 , 3</sup>		---	0.9	1.4	
Q <sub>gd</sub>	Gate-Drain Charge <sup>2 , 3</sup>		---	0.4	0.6	
T <sub>d(on)</sub>	Turn-On Delay Time <sup>2 , 3</sup>	V <sub>DD</sub> =30V , V <sub>GS</sub> =10V , R <sub>G</sub> =6 Ω I <sub>D</sub> =0.2A	---	3	6	ns
T <sub>r</sub>	Rise Time <sup>2 , 3</sup>		---	5	10	
T <sub>d(off)</sub>	Turn-Off Delay Time <sup>2 , 3</sup>		---	14	27	
T <sub>f</sub>	Fall Time <sup>2 , 3</sup>		---	9	17	
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> =30V , V <sub>GS</sub> =0V , F=1MHz	---	25.5	38	pF
C <sub>oss</sub>	Output Capacitance		---	17	26	
C <sub>rss</sub>	Reverse Transfer Capacitance		---	7.8	12	

### Drain-Source Diode Characteristics and Maximum Ratings

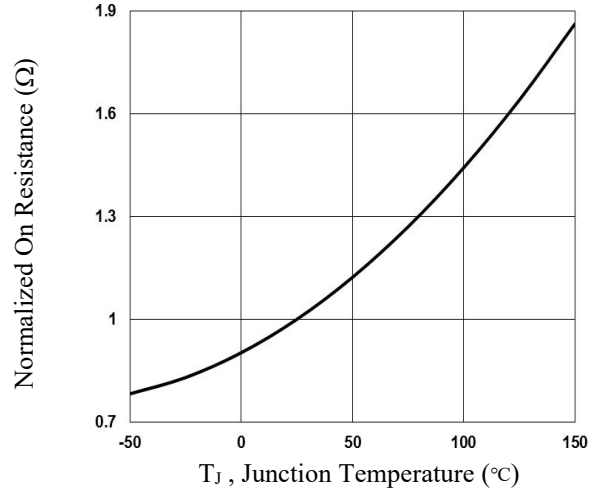
Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
I <sub>S</sub>	Continuous Source Current	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current	---	---	0.3	A
I <sub>SM</sub>	Pulsed Source Current		---	---	1.2	A
V <sub>SD</sub>	Diode Forward Voltage	V <sub>GS</sub> =0V , I <sub>S</sub> =1A , T <sub>J</sub> =25°C	---	---	1.2	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> =50V , I <sub>S</sub> =1A , dI/dt=100A/μs	---	3.4	---	ns
Q <sub>rr</sub>	Reverse Recovery Charge	T <sub>J</sub> =25°C	---	0.7	---	nC

#### Note :

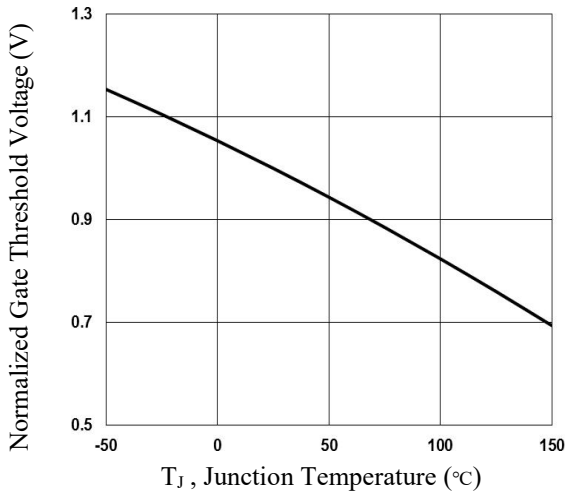
- 1.Repetitive Rating : Pulsed width limited by maximum junction temperature.
- 2 . The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2% .
3. Essentially independent of operating temperature.



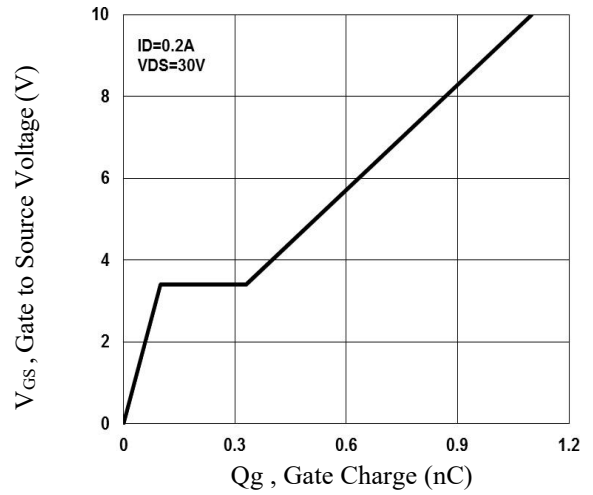
**Fig.1 Continuous Drain Current vs.  $T_C$**



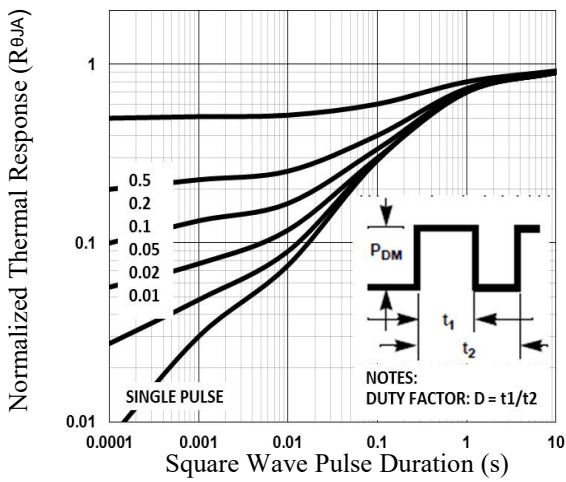
**Fig.2 Normalized R<sub>DSON</sub> vs.  $T_J$**



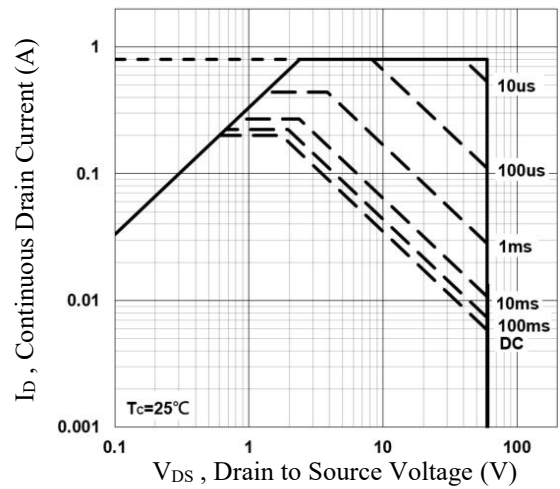
**Fig.3 Normalized  $V_{th}$  vs.  $T_J$**



**Fig.4 Gate Charge Waveform**

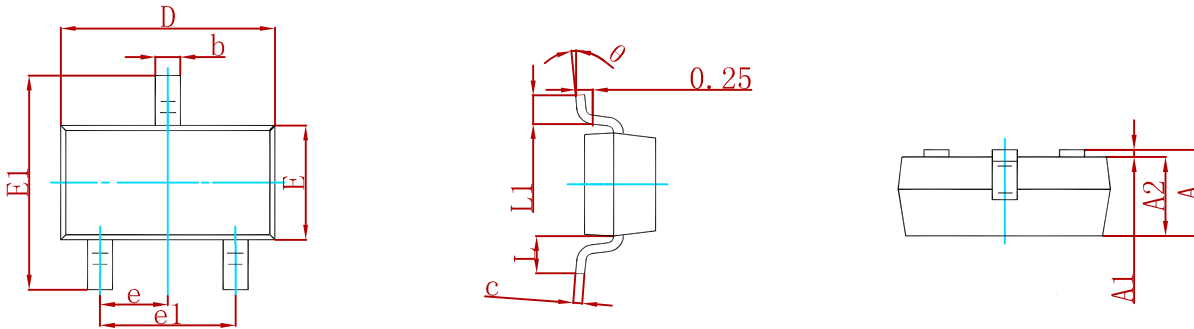


**Fig.5 Normalized Transient Impedance**



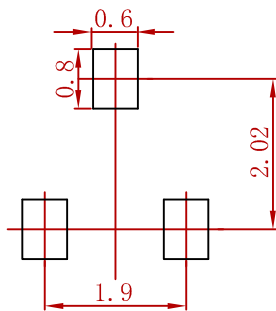
**Fig.6 Maximum Safe Operation Area**

**PACKAGE MECHANICAL DATA**



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min	Max	Min	Max
A	0.900	1.150	0.035	0.045
A1	0.000	0.100	0.000	0.004
A2	0.900	1.050	0.035	0.041
b	0.300	0.500	0.012	0.020
c	0.080	0.150	0.003	0.006
D	2.800	3.000	0.110	0.118
E	1.200	1.400	0.047	0.055
E1	2.250	2.550	0.089	0.100
e	0.950 TYP		0.037 TYP	
e1	1.800	2.000	0.071	0.079
L	0.550 REF		0.022 REF	
L1	0.300	0.500	0.012	0.020
θ	0°	8°	0°	8°

**Suggested Pad Layout**



- Note:
1. Controlling dimension: in millimeters.
  2. General tolerance: ± 0.05mm.
  3. The pad layout is for reference purposes only.

**REEL SPECIFICATION**

P/N	PKG	QTY
T2N7002AK-MS	SOT-23	3000

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